

N-Channel Enhancement Mode MOSFET

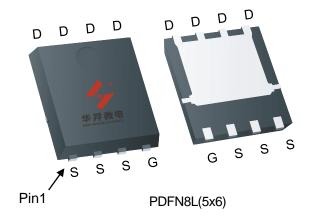
Feature

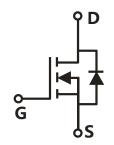
- 80V/185A $R_{DS(ON)} = 2.4 \text{ m}\Omega(\text{typ.}) \text{ @VGS} = 10V$
- 100% Avalanche Tested
- 100% DVDS
- Reliable and Rugged
- Halogen Free and Green Devices Available (RoHS Compliant)

Applications

- Switching application
- Li-battery protection
- DC-DC
- Motor control

Pin Description





Single N-Channel MOSFET

Ordering and Marking Information



Package Code C2: PDFN8L(5x6)

Date Code XYMXXXXXX

Note: HUAYI halogen free products contain molding compounds/die attach materials and 100% matte tin plate Termi-Nation finish; which are fully compliant with RoHS. HUAYI halogen free products meet or exceed the halogen free require-ments of IPC/JEDEC J-STD-020 for MSL classification at halogen free peak reflow temperature. HUAYI defines "Green" to mean halogen free (RoHS compliant) and halogen free (Br or Cl does not exceed 900ppm by weight in homogeneous material and total of Br and Cl does not exceed 1500ppm by weight).

HUAYI reserves the right to make changes, corrections, enhancements, modifications, and improvements to this pr-oduct and/or to this document at any time without notice.



Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit	
Common Ra	tings (Tc=25°C Unless Otherwise Noted)		,	1
VDSS	Drain-Source Voltage		80	V
Vgss	Gate-Source Voltage		±20	V
TJ	Junction Temperature Range		55. 475	°C
Tstg	Storage Temperature Range		-55 to 175	°C
ls	Source Current-Continuous(Body Diode) Tc=25°C		185	А
Mounted on	Large Heat Sink	,	,	1
Ідм	Pulsed Drain Current *	Tc=25°C	400	А
1			185	А
ID	In Continuous Drain Current	Tc=100°C	130.8	А
			211.3	W
P _D Maximum Power Dissipation		Tc=100°C	105.6	W
R₀uc	Thermal Resistance, Junction-to-Case		0.71	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient **		80	°C/W
Eas	Single Pulsed-Avalanche Energy *** L=0.3mH		551	mJ

Note:

- * Repetitive rating; pulse width limited by max.junction temperature.
- ** Surface mounted on 1in2 FR-4 board.
- *** Limited by TJmax , starting TJ=25°C, L = 0.3mH, Rg= 25Ω , Vgs =10V.

Electrical Characteristics(Tc =25°C Unless Otherwise Noted)

Complete	Donomoton	eter Test Conditions		HYG026N08NS1			
Symbol	Parameter			Тур.	Max	Unit	
Static Cha	Static Characteristics						
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V,I _{DS} =250μA	80	-	-	V	
	Drain to Source Leekage Current	Vps=80V,Vgs=0V	-	-	1	μA	
loss	Drain-to-Source Leakage Current	TJ=125°C	-	-	10	μA	
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250µA	2.2	3	3.8	V	
lgss	Gate-Source Leakage Current	Vgs=±20V,Vps=0V	-	-	±100	nA	
RDS(ON)	Drain-Source On-State Resistance	V _{GS} =10V,I _{DS} =20A	-	2.4	3	mΩ	
Diode Characteristics							
VsD	Diode Forward Voltage	Isp=20A,Vgs=0V	-	0.81	1.2	V	
trr	Reverse Recovery Time	lon-2014 dlon/dt-1001/up	-	27	-	ns	
Qrr	Reverse Recovery Charge	IsD=20A,dIsD/dt=100A/µs	-	30	-	nC	

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Electrical Characteristics (Cont.) (Tc =25°C Unless Otherwise Noted)

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Symbol Parameter		Test Conditions	Min	Тур.	Max	Unit
Dynamic (Dynamic Characteristics					
Rg	Gate Resistance	V _{GS} =0V,V _{DS} =0V,F=500KHz	-	1	-	Ω
Ciss	Input Capacitance	Vgs=0V,	-	7940	-	
Coss	Output Capacitance	V _{DS} =25V,	-	1695	-	pF
Crss	Reverse Transfer Capacitance	Frequency=500KHz	-	98	-	
td(ON)	Turn-on Delay Time		-	23	-	
Tr	Turn-on Rise Time	$V_{DD}=40V,R_{G}=2.5\Omega,$	-	34	-	
td(OFF)	Turn-off Delay Time	Ips=20A,Vgs=10V	-	53	-	ns
Tf	Turn-off Fall Time		-	28	-	
Gate Charge Characteristics						
Qg	Total Gate Charge(V _{GS} =10V)		-	115	-	
Qgs	Gate-Source Charge	\/ _64\/ _20\	-	39	-	nC
Qgd	Gate-Drain Charge	V_{DS} =64V, I_{DS} =20A	-	15	-	
V _{plateau}	Gate plateau voltage		-	4.6	-	V

Note: *Pulse test, pulse width ≤ 300 us, duty cycle $\leq 2\%$



Typical Operating Characteristics

Figure 1: Power Dissipation

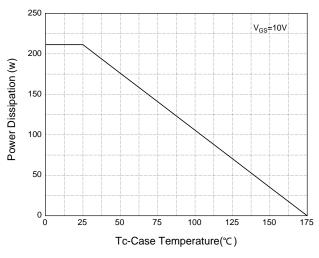


Figure 3: Safe Operation Area

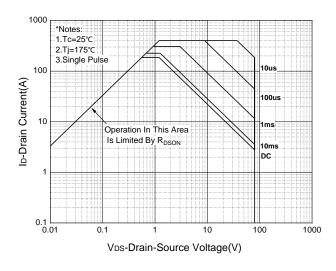


Figure 5: Output Characteristics

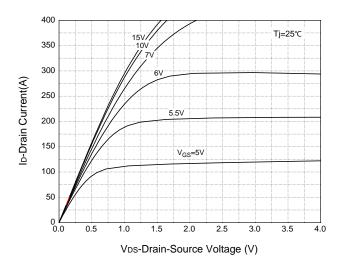


Figure 2: Drain Current

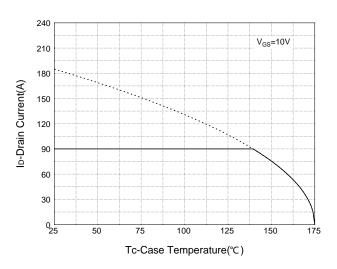


Figure 4: Thermal Transient Impedance

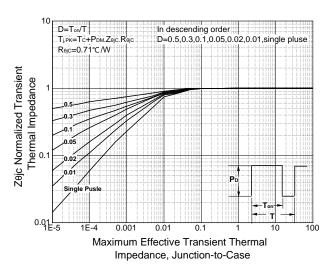
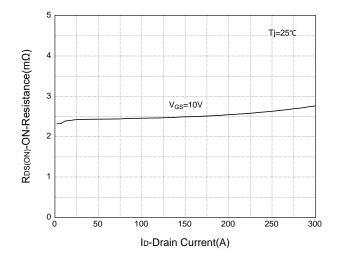


Figure 6: Drain-Source On Resistance





Typical Operating Characteristics(Cont.)

Figure 7: On-Resistance vs. Temperature

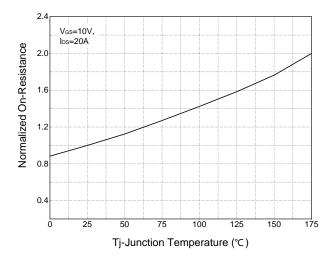


Figure 8: Source-Drain Diode Forward

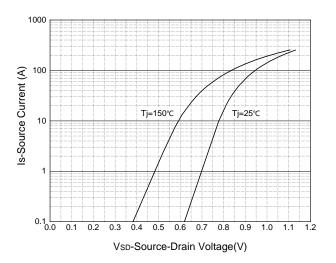


Figure 9: Capacitance Characteristics

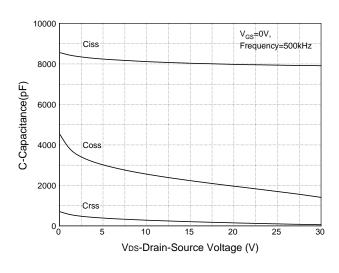
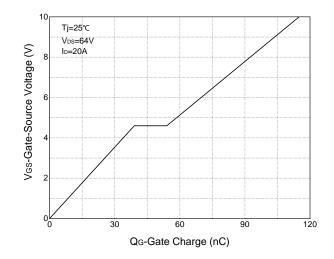
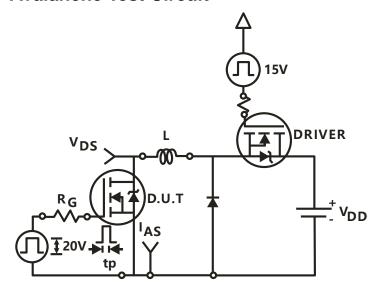


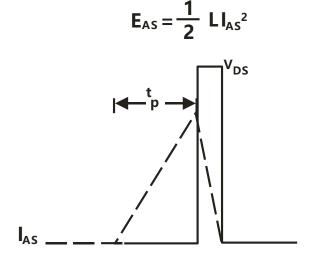
Figure 10: Gate Charge Characteristics



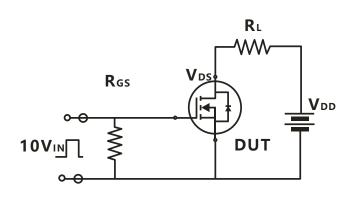


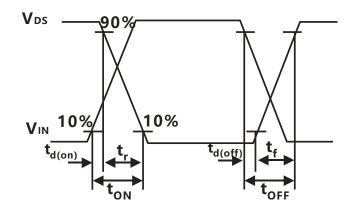
Avalanche Test Circuit



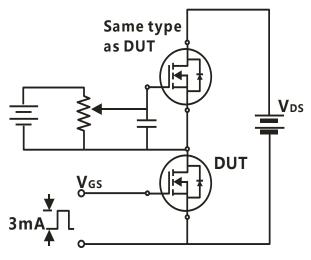


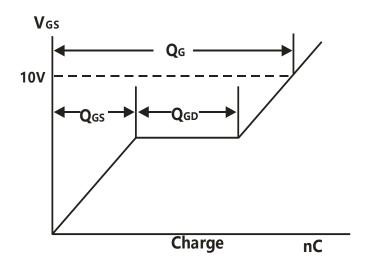
Switching Time Test Circuit





Gate Charge Test Circuit







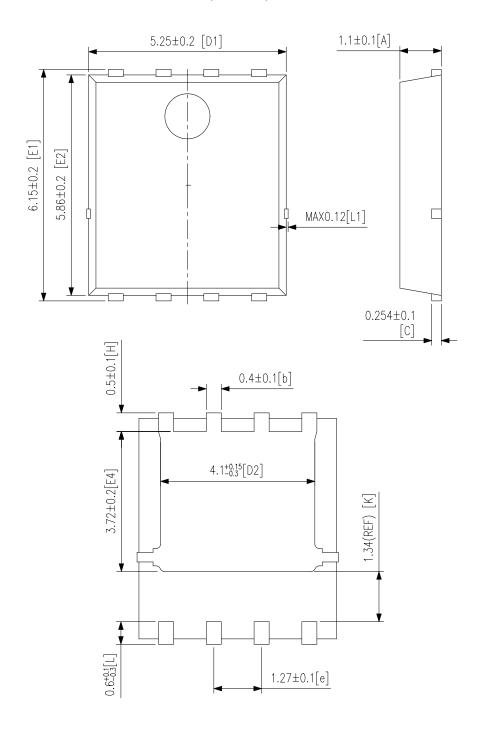
Device Per Unit

Package Type	Unit	Quantity
PDFN8L(5x6)	Reel	5000

Package Information

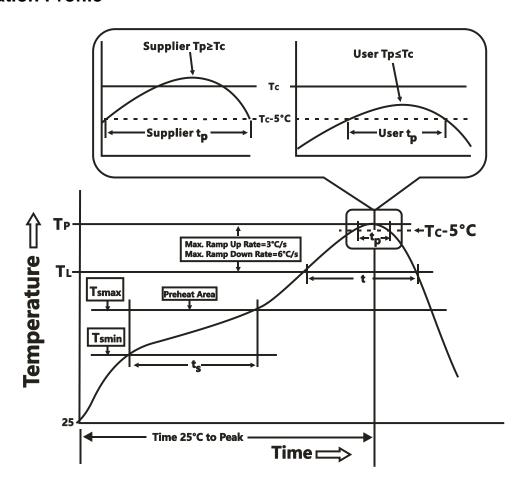
PDFN8L(5x6)

(unit:mm)





Classification Profile



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly			
Preheat & Soak					
Temperature min (T _{smin})	100 °C	150 °C			
Temperature max (T _{smax})	150 °C	200 °C			
Time (Tsmin to Tsmax) (t _s)	60-120 seconds	60-120 seconds			
Average ramp-up rate	3 °C/second max.	3°C/second max.			
(T _{smax} to T _P)	5 C/second max.				
Liquidous temperature (T _L)	183 °C	217 °C			
Time at liquidous (t _L)	60-150 seconds	60-150 seconds			
Peak package body Temperature	See Classification Temp in table 1	SeeClassification Tempin table 2			
(T _P)*	See Classification Temp in table 1				
Time (t _P)** within 5°C of the specified	20**	30** seconds			
classification temperature (T _c)	20** seconds				
Average ramp-down rate (Tpto Tsmax)	6 °C/second max.	6 °C/second max.			
Time 25°C to peak temperature	6 minutes max.	8 minutes max.			

^{*}Tolerance for peak profile Temperature (Tp) is defined as a supplier minimum and a user maximum.

^{**} Tolerance for time at peak profile temperature (t_p) is defined as a supplier minimum and a user maximum.

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Table 1.SnPb Eutectic Process – Classification Temperatures (Tc)

Package Thickness	Volume mm³ <350	Volume mm³ ≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2.Pb-free Process – Classification Temperatures (Tc)

Package	Volume mm ³	Volume mm ³	Volume mm³
Thickness	<350	350-2000	≥2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
HTRB	JESD-22, A108	168/500 Hrs, Bias @ 150°C
HTGB	JESD-22, A108	168 /500 Hrs, V _{gs} 100% @ 150°C
PCT	JESD-22, A102	96 Hrs, 100%RH, 2atm, 121°C
ТСТ	JESD-22, A104	250/500 Cycles, -55°C~150°C

Customer Service

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